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(12) **United States Design Patent** (10) **Patent No.:** **US D799,577 S**  
**Ushio et al.** (45) **Date of Patent:** **\*\* Oct. 10, 2017**

(54) **DARK FIELD ILLUMINATION DEVICE FOR MICROSCOPE**

FOREIGN PATENT DOCUMENTS

(71) Applicant: **OLYMPUS CORPORATION**, Tokyo (JP)

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(73) Assignee: **OLYMPUS CORPORATION**, Tokyo (JP)

Japanese Notice dated Apr. 26, 2016 in related Japanese Patent Application No. 2015-025194.

(\*\*) Term: **15 Years**

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(21) Appl. No.: **29/563,960**

(57) **CLAIM**

(22) Filed: **May 10, 2016**

The ornamental design for a dark field illumination device for microscope, as shown and described.

(30) **Foreign Application Priority Data**

**DESCRIPTION**

Nov. 11, 2015 (JP) ..... 2015-025194

(51) **LOC (10) Cl.** ..... **16-06**

(52) **U.S. Cl.**  
USPC ..... **D16/136**

(58) **Field of Classification Search**  
USPC ..... D24/138; D26/37, 62; D16/130–136  
CPC ..... F21L 2/00; F21L 4/00; F21L 4/005; F21L 17/00; F21L 13/08; F21Y 2101/00; F21V 21/406; F21W 2131/406; F21W 2131/407  
See application file for complete search history.

FIG. 1 is a bottom, rear and left side perspective view of a dark field illumination device for microscope, showing our new design;  
FIG. 2 is top, front and right side perspective view thereof;  
FIG. 3 is a front elevational view thereof;  
FIG. 4 is a rear elevational view thereof;  
FIG. 5 is a right side elevational view thereof;  
FIG. 6 is a left side elevational view thereof;  
FIG. 7 is a top plan view thereof;  
FIG. 8 is a bottom plan view thereof;  
FIG. 9 is a cross-sectional view taken along a line 9-9 in FIG. 6 in which the internal mechanisms are omitted to better illustrate the contour thereof; and,  
FIG. 10 is a perspective view of the dark field illumination device for microscope inserted into a microscope.  
The dash dot broken lines in FIG. 9 depict portions of the dark field illumination device for microscope that form no part of the claimed design. The evenly segmented broken lines in FIG. 10 depict environmental subject matter only and form no part of the claimed design.

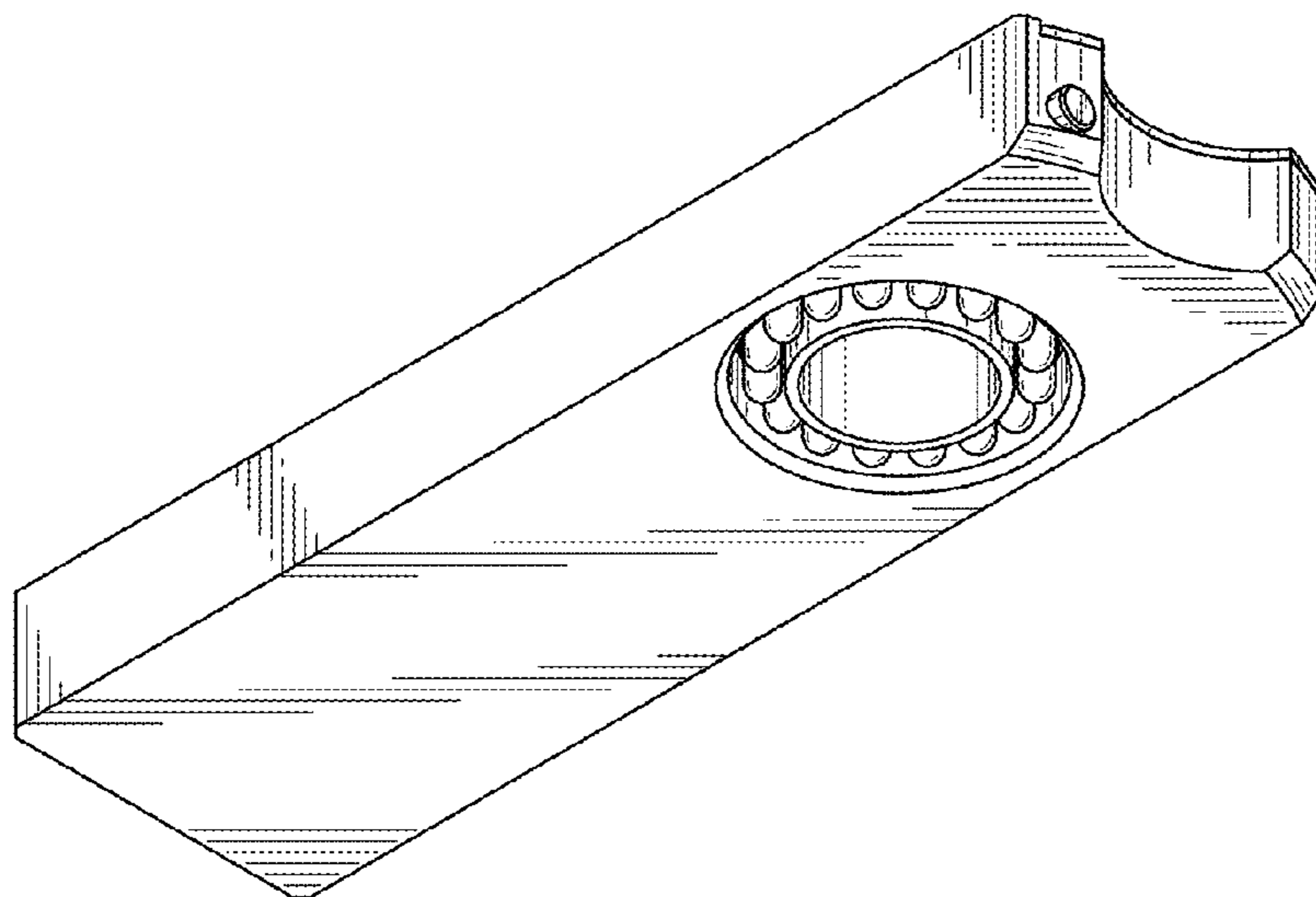
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**1 Claim, 5 Drawing Sheets**



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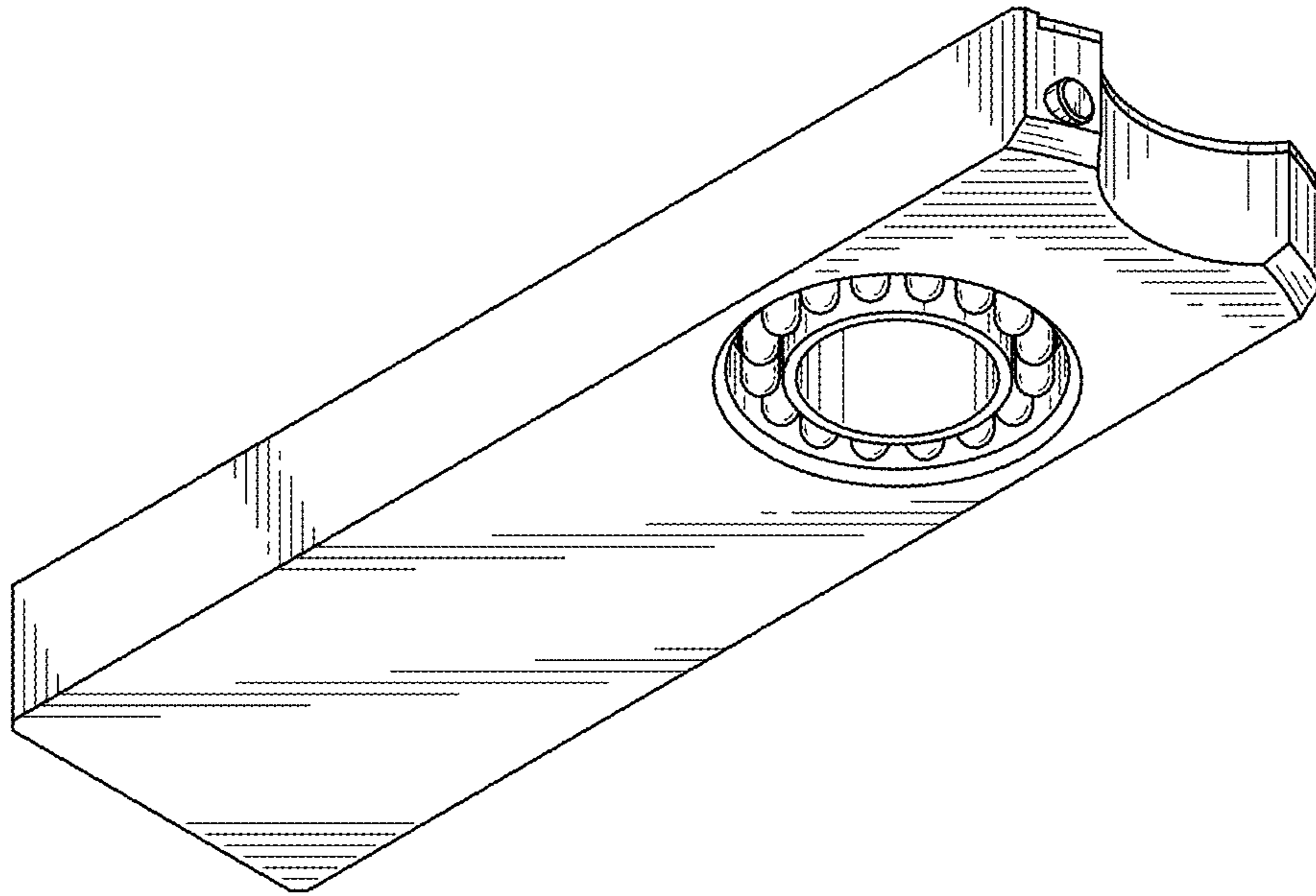
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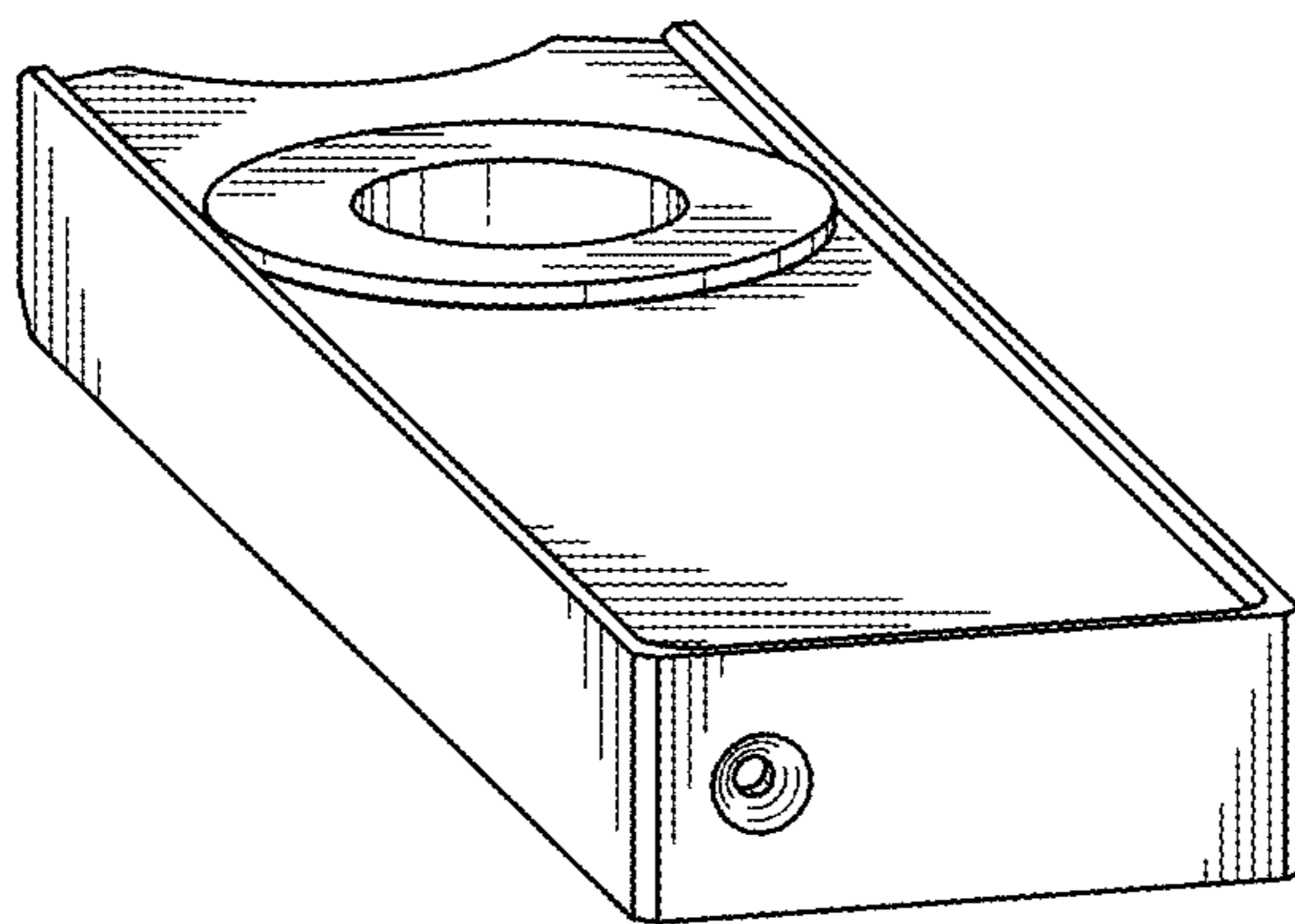
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*FIG. 1*



*FIG. 2*



*FIG. 3*



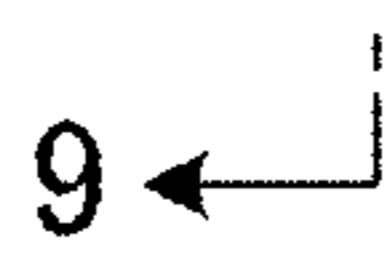
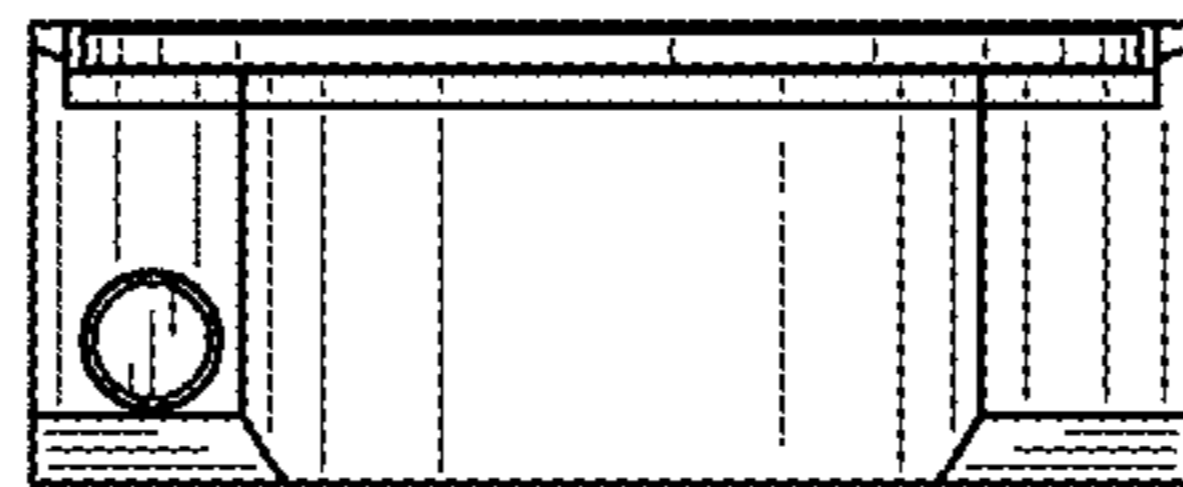
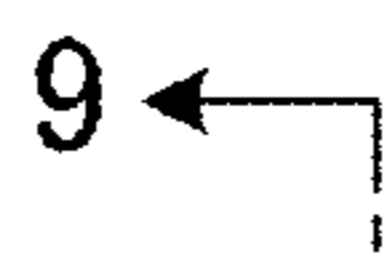
*FIG. 4*



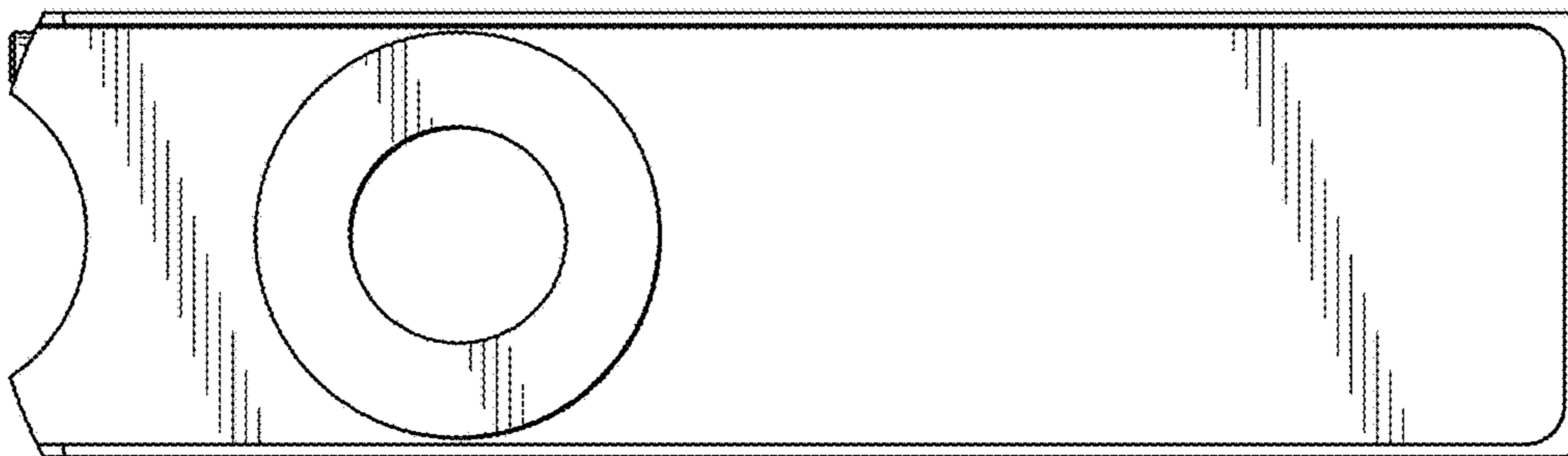
*FIG. 5*



*FIG. 6*



*FIG. 7*



*FIG. 8*

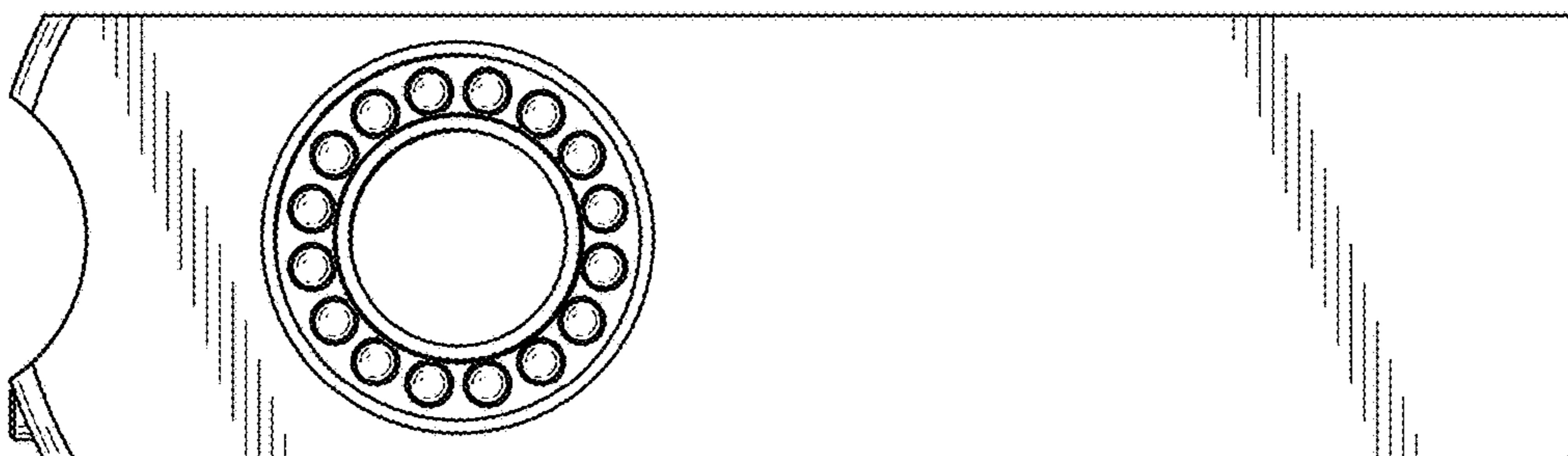


FIG. 9

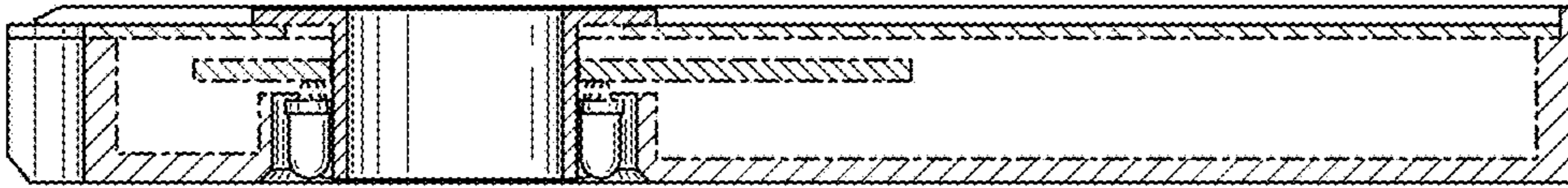


FIG. 10

